


05/09/90

ISSUE CLASSIFICATION	
Class	Subclass

PATENT NUMBER

U.S. **UTILITY** Patent Application

<p>O.I.P.E.</p> <p>SCANNED <u>HKm²</u> Q.A. <u>EW</u></p>	<p>PATENT DATE</p>
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APPLICATION NO. 09/852111	CONT/PRIOR F	CLASS 073 378	SUBCLASS 89	ART UNIT 2856 3883	EXAMINER 
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APPLICANTS

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Method and apparatus for measuring thin film, and thin film deposition system

PTO-2040
12/89[illegible]

<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS		CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims
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